TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74LCX157F,TC74LCX157FN,TC74LCX157FT

Low Voltage Quad 2-Channel Multiplexer with 5 V Tolerant Inputs and Outputs

Note: xxxFN (JEDEC SOP) is not available in Japan.

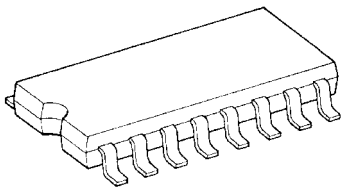
The TC74LCX157F/FN/FT is a high-performance CMOS multiplexer. Designed for use in 3.3-V systems, it achieves high-speed operation while maintaining the CMOS low power dissipation.

The device is designed for low-voltage (3.3 V) V_{CC} applications, but it could be used to interface to 5-V supply environment for inputs.

It consists of four 2-input digital multiplexers with common SELECT and $\overline{ST}$ inputs. When the $\overline{ST}$ input is held "H" level, selection of data is inhibited and all the outputs become "L" level. The SELECT decoding determines whether the A or B inputs get routed to their corresponding Y outputs.

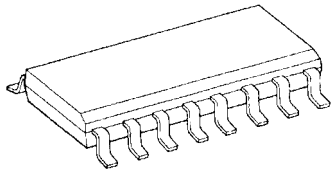
All inputs are equipped with protection circuits against static discharge.

TC74LCX157F



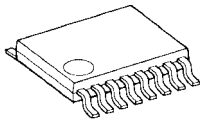
SOP16-P-300-1.27

TC74LCX157FN



SOL16-P-150-1.27

TC74LCX157FT



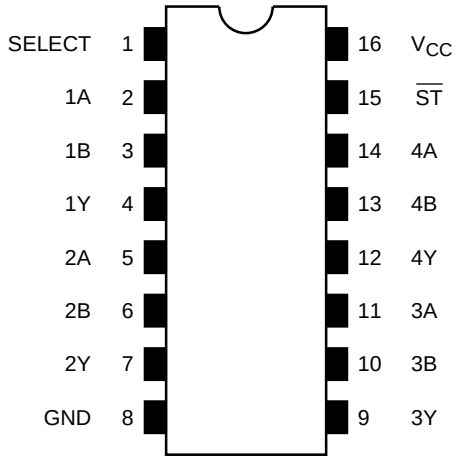
TSSOP16-P-0044-0.65

Weight
SOP16-P-300-1.27: 0.18 g (typ.)
SOL16-P-150-1.27: 0.12 g (typ.)
TSSOP16-P-0044-0.65: 0.06 g (typ.)

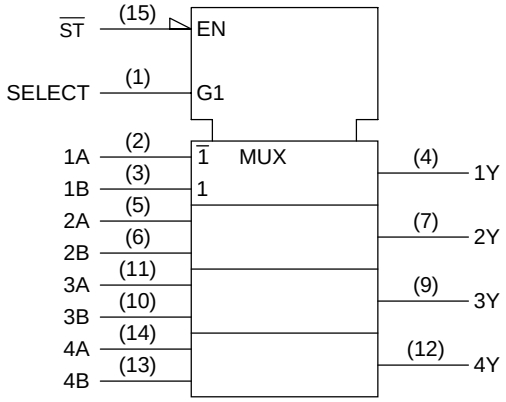
Features

- Low-voltage operation: V_{CC} = 2.0 to 3.6 V
- High-speed operation: t_{pd} = 5.8 ns (max) (V_{CC} = 3.0 to 3.6 V)
- Ouput current: $|I_{OH}|/I_{OL}$ = 24 mA (min) (V_{CC} = 3.0 V)
- Latch-up performance: ±500 mA
- Available in JEDEC SOP, JEITA SOP and TSSOP
- Power-down protection provided on all inputs and outputs
- Pin and function compatible with the 74 series (74AC/VHC/HC/F/ALS/LS etc.) 157 type

Pin Assignment (top view)



IEC Logic Symbol

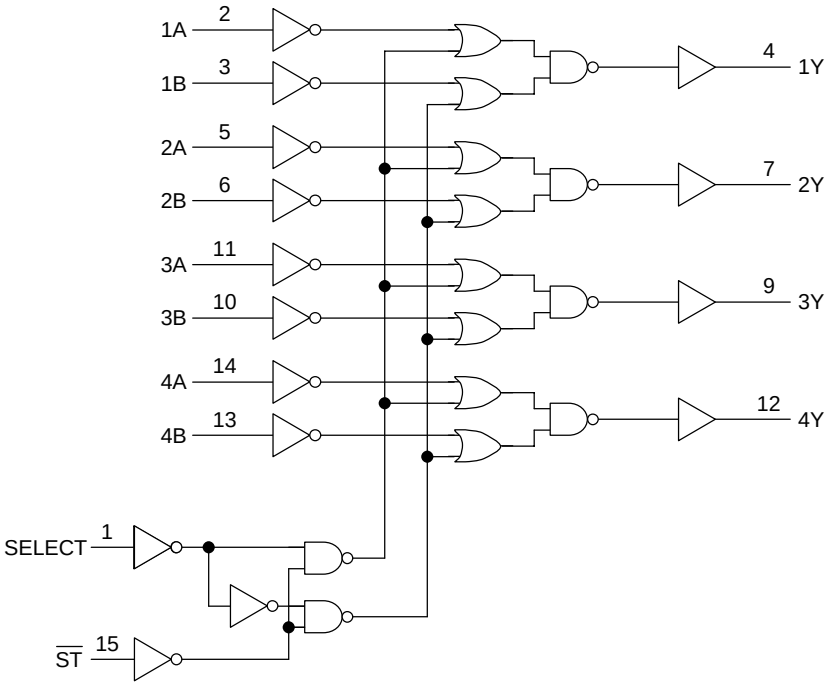


Truth Table

Inputs				Outputs
$\overline{ST}$	SELECT	A	B	Y
H	X	X	X	L
L	L	L	X	L
L	L	H	X	H
L	H	X	L	L
L	H	X	H	H

X: Don’t care

System Diagram



Maximum Ratings

Characteristics	Symbol	Rating	Unit
Power supply voltage	V_{CC}	−0.5 to 7.0	V
DC input voltage	V_{IN}	−0.5 to 7.0	V
DC output voltage	V_{OUT}	−0.5 to 7.0 (Note 1) −0.5 to V_{CC} + 0.5 (Note 2)	V
Input diode current	I_{IK}	−50	mA
Output diode current	I_{OK}	±50 (Note 3)	mA
DC output current	I_{OUT}	±50	mA
Power dissipation	P_D	180	mW
DC V_{CC}/ground current	I_{CC}/I_{GND}	±100	mA
Storage temperature	T_{stg}	−65 to 150	°C

Note 1: $V_{CC} = 0$ V

Note 2: High or low state. I_{OUT} absolute maximum rating must be observed.

Note 3: $V_{OUT} < GND$, $V_{OUT} > V_{CC}$

Recommended Operating Conditions

Characteristics	Symbol	Rating	Unit
Power supply voltage	V_{CC}	2.0 to 3.6	V
		1.5 to 3.6 (Note 4)	
Input voltage	V_{IN}	0 to 5.5	V
Output voltage	V_{OUT}	0 to 5.5 (Note 5)	V
		0 to V_{CC} (Note 6)	
Output current	I_{OH}/I_{OL}	±24 (Note 7)	mA
		±12 (Note 8)	
Operating temperature	T_{opr}	−40 to 85	°C
Input rise and fall time	dt/dv	0 to 10 (Note 9)	ns/V

Note 4: Data retention only

Note 5: V_{CC} = 0 V

Note 6: High or low state

Note 7: V_{CC} = 3.0 to 3.6 V

Note 8: V_{CC} = 2.7 to 3.0 V

Note 9: V_{IN} = 0.8 to 2.0 V, V_{CC} = 3.0 V

Electrical Characteristics

DC Characteristics (Ta = –40 to 85°C)

Characteristics		Symbol	Test Condition		V_{CC} (V)	Min	Max	Unit
Input voltage	H-level	V_{IH}	—		2.7 to 3.6	2.0	—	V
	L-level	V_{IL}	—		2.7 to 3.6	—	0.8	
Output voltage	H-level	V_{OH}	V_{IN} = V_{IH} or V_{IL}	I_{OH} = −100 μA	2.7 to 3.6	V_{CC} −0.2	—	V
				I_{OH} = −12 mA	2.7	2.2	—	
				I_{OH} = −18 mA	3.0	2.4	—	
				I_{OH} = −24 mA	3.0	2.2	—	
	L-level	V_{OL}	V_{IN} = V_{IH} or V_{IL}	I_{OL} = 100 μA	2.7 to 3.6	—	0.2	
				I_{OL} = 12 mA	2.7	—	0.4	
				I_{OL} = 16 mA	3.0	—	0.4	
				I_{OL} = 24 mA	3.0	—	0.55	
Input leakage current		I_{IN}	V_{IN} = 0 to 5.5 V		2.7 to 3.6	—	±5.0	μA
Power-off leakage current		I_{OFF}	V_{IN}/V_{OUT} = 5.5 V		0	—	10.0	μA
Quiescent supply current		I_{CC}	V_{IN} = V_{CC} or GND		2.7 to 3.6	—	10.0	μA
			V_{IN} = 3.6 to 5.5 V		2.7 to 3.6	—	±10.0	
Increase in Icc per input		ΔI_{CC}	V_{IH} = V_{CC} − 0.6 V		2.7 to 3.6	—	500	

AC Characteristics (Ta = –40 to 85°C)

Characteristics	Symbol	Test Condition	V_{CC} (V)	Min	Max	Unit
Propagation delay time (A, B-Y)	t_{pLH} t_{pHL}	Figure 1, Figure 2	2.7	—	6.3	ns
			3.3 ± 0.3	1.5	5.8	
Propagation delay time (SELECT-Y)	t_{pLH} t_{pHL}	Figure 1, Figure 2	2.7	—	8.0	ns
			3.3 ± 0.3	1.5	7.0	
Propagation delay time ($\overline{ST}$ -Y)	t_{pLH} t_{pHL}	Figure 1, Figure 2	2.7	—	8.0	ns
			3.3 ± 0.3	1.5	7.0	
Output to output skew	t_{osLH} t_{osHL}	(Note 10)	2.7	—	—	ns
			3.3 ± 0.3	—	1.0	

Note 10: Parameter guaranteed by design.
($t_{osLH} = |t_{pLHm} - t_{pLHn}|$, $t_{osHL} = |t_{pHLm} - t_{pHLn}|$)

Dynamic Switching Characteristics
(Ta = 25°C, input: $t_r = t_f = 2.5$ ns, $C_L = 50$ pF, $R_L = 500\ \Omega$)

Characteristics	Symbol	Test Condition	V_{CC} (V)	Typ.	Unit
Quiet output maximum dynamic V_{OL}	V_{OLP}	V_{IH} = 3.3 V, V_{IL} = 0 V	3.3	0.8	V
Quiet output minimum dynamic V_{OL}	$\|V_{OLV}\|$	V_{IH} = 3.3 V, V_{IL} = 0 V	3.3	0.8	V

Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	V_{CC} (V)	Typ.	Unit
Input capacitance	C_{IN}	—	3.3	7	pF
Output capacitance	C_{OUT}	—	0	8	pF
Power dissipation capacitance	C_{PD}	f_{IN} = 10 MHz (Note 11)	3.3	25	pF

Note 11: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.
Average operating current can be obtained by the equation:
$I_{CC\ (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

AC Test Circuit

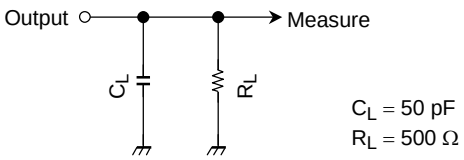


Figure 1

AC Waveform

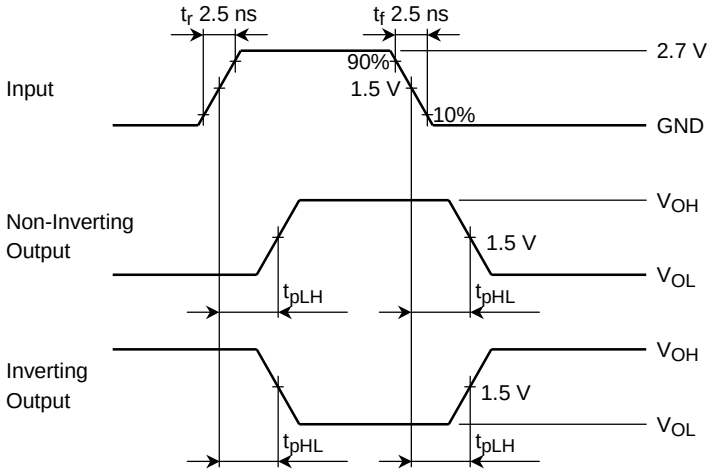
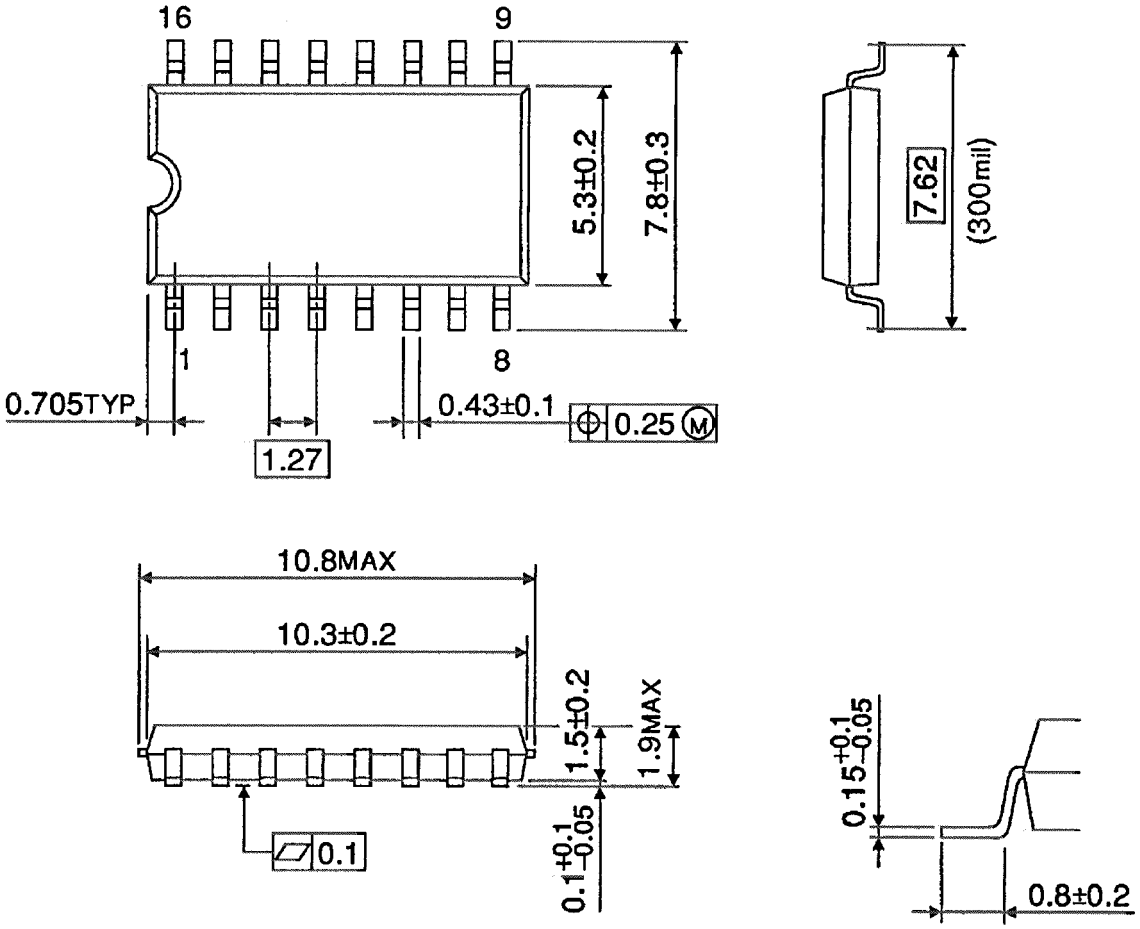


Figure 2 t_{pLH}, t_{pHL}

Package Dimensions

SOP16-P-300-1.27 Unit : mm

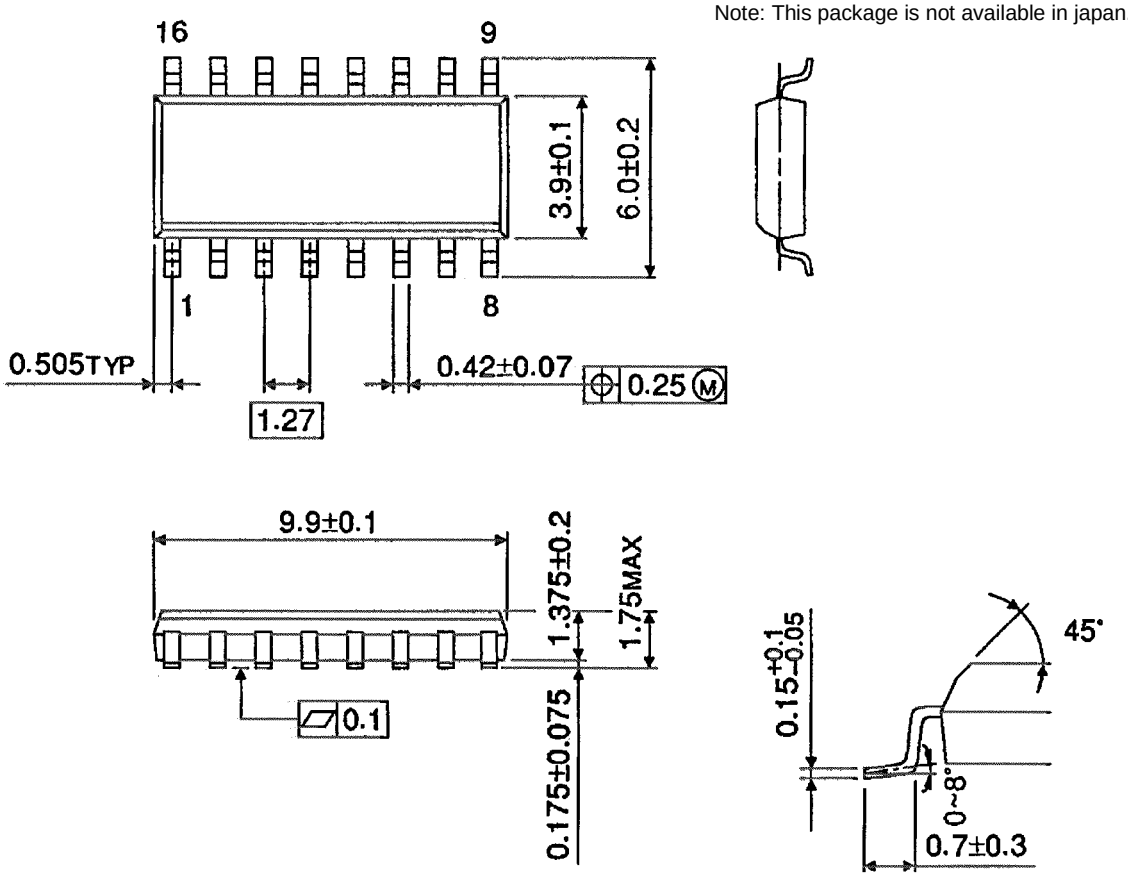


Weight: 0.18 g (typ.)

Package Dimensions

SOL16-P-150-1.27 Unit : mm

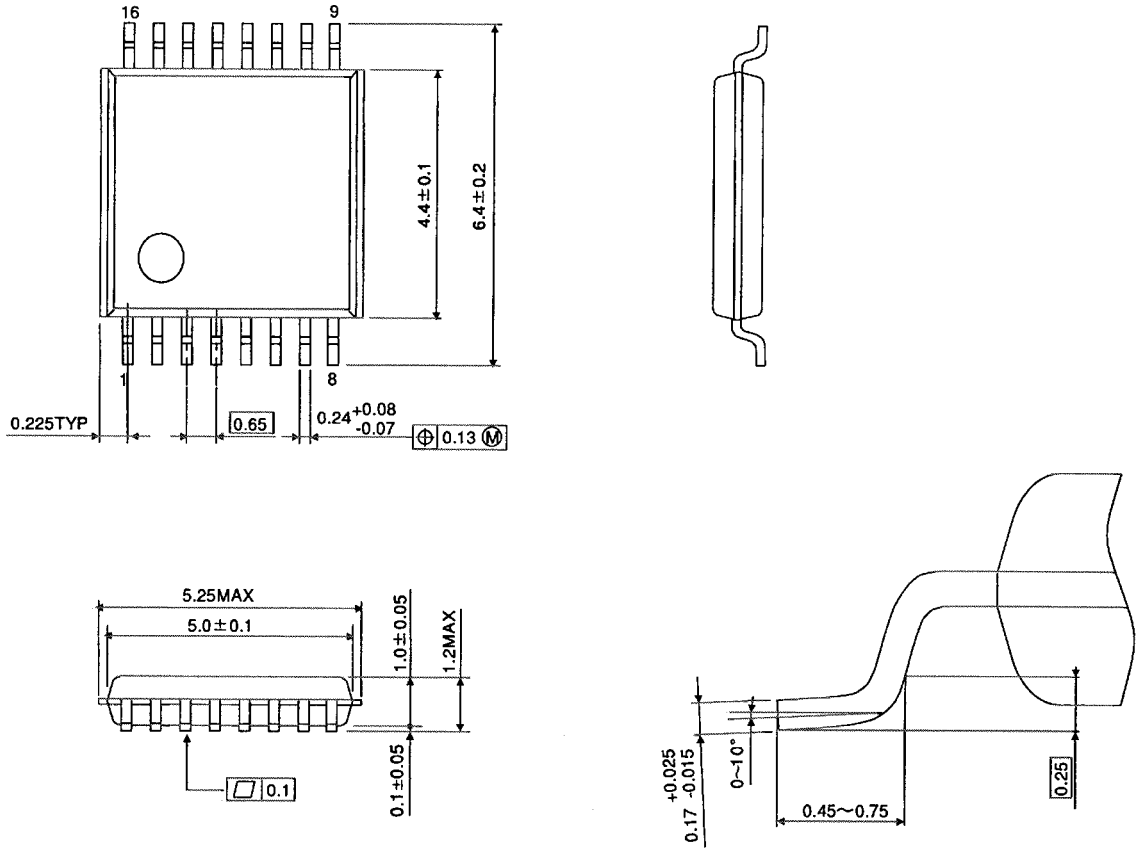
Note: This package is not available in japan.



Weight: 0.12 g (typ.)

Package Dimensions

TSSOP16-P-0044-0.65 Unit : mm



Weight: 0.06 g (typ.)

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